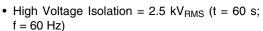


# 1N90L-TF1-T-VB Datasheet N-Channel 950 V (D-S) Power MOSFET

PRODUCT SUMMA	RY	
V <sub>DS</sub> (V)	95	50
$R_{DS(on)}\left(\Omega\right)$	V <sub>GS</sub> = 10 V	3.5
Q <sub>g</sub> (Max.) (nC)	78	
Q <sub>gs</sub> (nC)	10	
Q <sub>gd</sub> (nC)	42	
Configuration	Sing	le

#### **FEATURES**

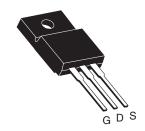
· Isolated Package

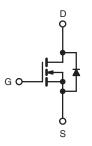




- Sink to Lead Creepage Distance = 4.8 mm
- · Dynamic dV/dt Rating
- · Low Thermal Resistance
- Lead (Pb)-free Available







N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T	<sub>C</sub> = 25 °C, unless otherw	rise noted		
PARAMETER		SYMBOL	LIMIT	UNIT
Drain-Source Voltage		$V_{DS}$	950	V
Gate-Source Voltage		$V_{GS}$	± 20	V
Continuous Drain Current	V <sub>GS</sub> at 10 V T <sub>C</sub> = 25 °C	I <sub>D</sub>	3.0	
Continuous Drain Current	$V_{GS}$ at 10 $V_{CS}$ $T_{C} = 100 ^{\circ}C$		2.3	Α
Pulsed Drain Current <sup>a</sup>	I <sub>DM</sub>	10	1	
Linear Derating Factor		0.28	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>	E <sub>AS</sub>	220	mJ	
Repetitive Avalanche Currenta	I <sub>AR</sub>	1.9	Α	
Repetitive Avalanche Energy <sup>a</sup>	E <sub>AR</sub>	3.5	mJ	
Maximum Power Dissipation	T <sub>C</sub> = 25 °C	$P_{D}$	35	W
Peak Diode Recovery dV/dtc	dV/dt	1.5	V/ns	
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	00	
Soldering Recommendations (Peak Temperature)	for 10 s	-	300 <sup>d</sup>	°C
Manustine Terror	6-32 or M3 screw		10	lbf ⋅ in
Mounting Torque	0-32 OF IVIS SCIEW		1.1	N · m

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b.  $V_{DD}=50~V$ , starting  $T_J=25~^{\circ}C$ ,  $L=115~^{\circ}MH$ ,  $R_G=25~^{\circ}\Omega$ ,  $I_{AS}=1.9~A$  (see fig. 12). c.  $I_{SD}\leq 3.6~A$ ,  $dI/dt\leq 70~A/\mu s$ ,  $V_{DD}\leq 600$ ,  $T_J\leq 150~^{\circ}C$ .

- d. 1.6 mm from case.

<sup>\*</sup> Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RAT	<b>FINGS</b>			
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	65	°C/W
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	3.6	C/VV

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static		·					
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		950	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	ce to 25 °C, I <sub>D</sub> = 1 mA	-	1.1	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>		V <sub>GS</sub> = ± 20 V		-	± 100	nA
Zava Cata Valtaga Dvain Cuvvant	1	V <sub>DS</sub> = 900 V, V <sub>GS</sub> = 0 V		-	-	100	μ. Λ
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 720 \	/, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	500	μΑ
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 1.1 A <sup>b</sup>	-	3.5	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> =	= 50 V, I <sub>D</sub> = 1.1 A <sup>b</sup>	1.7	-	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 \text{ V}, \\ V_{DS} = 25 \text{ V},$		-	1200	-	
Output Capacitance	C <sub>oss</sub>			-	320	-	
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1	.0 MHz, see fig. 5	-	200	-	pF
Drain to Sink Capacitance	С	f = 1.0 MHz		-	12	-	
Total Gate Charge	Qg		I <sub>D</sub> = 3.6 A, V <sub>DS</sub> = 360 V, see fig. 6 and 13 <sup>b</sup>	-	-	78	nC
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V		-	-	10	
Gate-Drain Charge	Q <sub>gd</sub>	1		-	-	42	
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD} = 450 \text{ V}, I_{D} = 3.6 \text{ A},$ $R_{G} = 12 \Omega, R_{D} = 120 \Omega,$ see fig. $10^{b}$		-	14	-	- ns
Rise Time	t <sub>r</sub>			-	25	-	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	90	-	
Fall Time	t <sub>f</sub>			-	30	-	
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	- nH
Internal Source Inductance	L <sub>S</sub>			-	7.5	-	
Drain-Source Body Diode Characteristic	s			•			
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	1.9	А
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	7.6	
Body Diode Voltage	$V_{SD}$	$T_J$ = 25 °C, $I_S$ = 1.9 A, $V_{GS}$ = 0 $V^b$		-	-	1.8	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T 25 °C I-	- 3.6.4 dl/dt - 100.4/usb	-	430	650	ns
Body Diode Reverse Recovery Charge	$Q_{rr}$	$T_J = 25 ^{\circ}\text{C}, I_F = 3.6 \text{A},  \text{dI/dt} = 100 \text{A/}\mu\text{s}^b$		-	1.4	2.1	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic tu	n-on is dominated by L <sub>S</sub> and L <sub>D</sub> )			_D)	

#### Notes

2

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width  $\leq$  300  $\mu s$ ; duty cycle  $\leq$  2 %.



#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

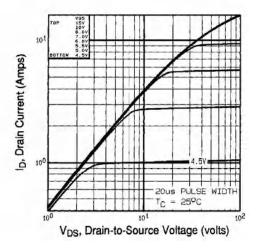


Fig. 1 - Typical Output Characteristics,  $T_C = 25$  °C

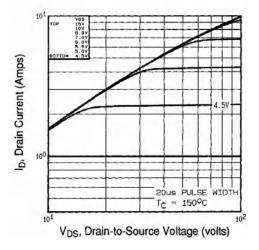


Fig. 2 - Typical Output Characteristics,  $T_C = 150 \, ^{\circ}C$ 

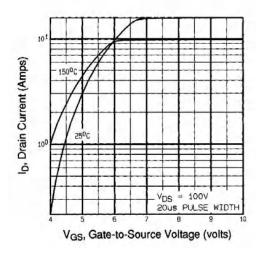


Fig. 3 - Typical Transfer Characteristics

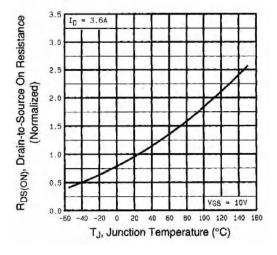


Fig. 4 - Normalized On-Resistance vs. Temperature



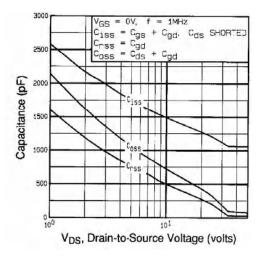


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

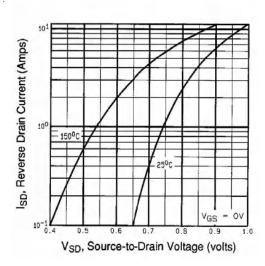


Fig. 7 - Typical Source-Drain Diode Forward Voltage

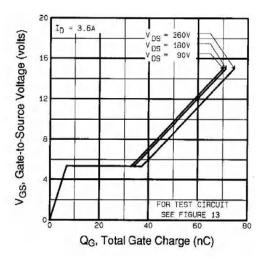


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

4

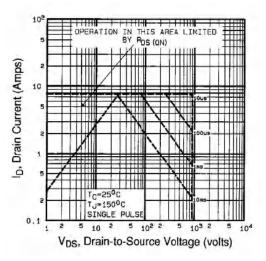


Fig. 8 - Maximum Safe Operating Area



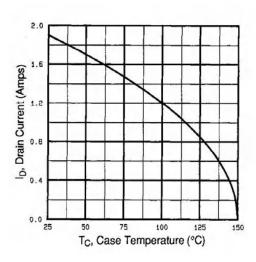


Fig. 9 - Maximum Drain Current vs. Case Temperature

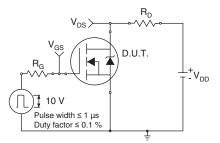


Fig. 10a - Switching Time Test Circuit

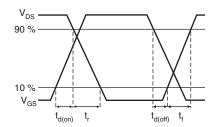


Fig. 10b - Switching Time Waveforms

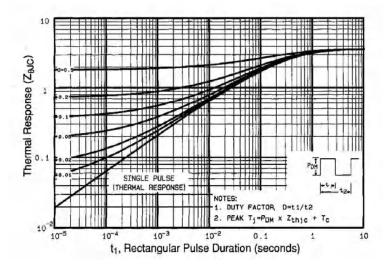


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

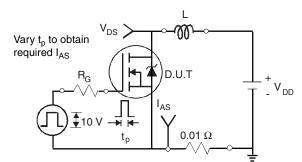


Fig. 12a - Unclamped Inductive Test Circuit

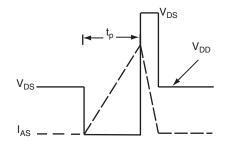


Fig. 12b - Unclamped Inductive Waveforms



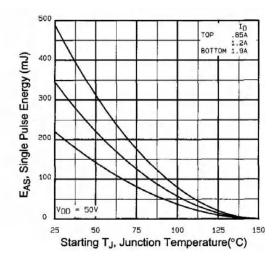


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

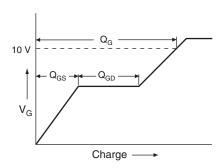


Fig. 13a - Basic Gate Charge Waveform

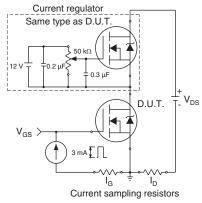
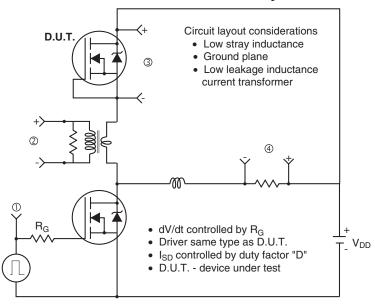


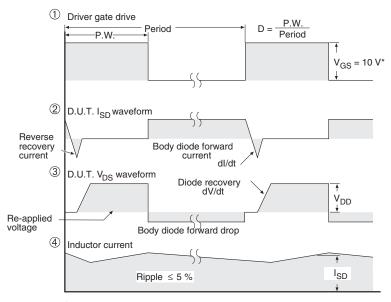
Fig. 13b - Gate Charge Test Circuit



7

## Peak Diode Recovery dV/dt Test Circuit



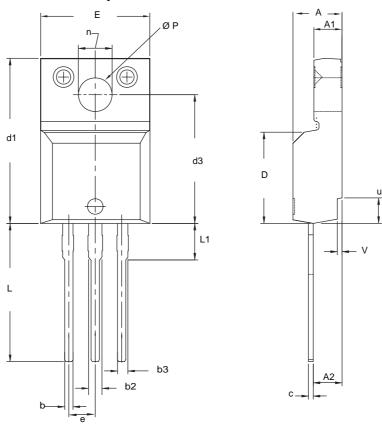


\*  $V_{GS} = 5 V$  for logic level devices

Fig.14 - For N-Channel



### **TO-220 FULLPAK (HIGH VOLTAGE)**



DIM.	MILLIN	METERS	INCHES	
	MIN.	MAX.	MIN.	MAX.
Α	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
С	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
Е	10.360	10.630	0.408	0.419
е	2.54	BSC	0.100 BSC	
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
ØΡ	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
V	0.400	0.500	0.016	0.020

## ECN: X09-0126-Rev. B, 26-Oct-09 DWG: 5972

#### Notes

- To be used only for process drawing.
   These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
   All critical dimensions should C meet C<sub>pk</sub> > 1.33.
   All dimensions include burst and plating thickness.

- 5. No chipping or package damage.



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